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From NEMS to Nanowires and their Front-End co-integration with CMOS for enhanced sensing performances

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Outline

Introduction

- Technological platforms in NEMSIC
 - Sensing application
 - Power management application
 - Examples of Devices fabricated in NEMSIC
 - Sensing application
 - Power management application
- Conclusion

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- 8

NEMS&Nanowires...more than miniaturization of MEMS

Motivations :

- NEMS/nanowires devices in thin Si layers
 - Benefit of NEMS (miniature size, low power, high resonance frequency&quality factor, NEMS arrays, sensing networks)
- NEMS/nanowire-IC integration : monolithic integration, 3D approaches...
 - Reduce cost, size and power consumption
- Toward new applications :
 - Low-cost & RF applications : nano-accelerometers, nano-resonators
 - New applications : mass sensor (gaz and bio sensors), NEMS switches, SGFET, memory,...

Issues :

- NEMS/nanowires challenges in physics : quantum phenomenon (Casimir force, charge quantification), noise processes, transduction & detection
- Transduction principle: capacitive, MOS (SG-FET, planar), piezoresistance...
- Manufacturing of NEMS/nanowires in thin Si layers, packaging
- Characterization of NEMS/nanowires (morphology, electrical...)



NEMS for mass-sensing

NEMS resonators for ultrasensitive mass detection

Shift of NEMS resonant frequency caused by mass loading Various functionalizations to enhance selectivity (multi-gaz sensing)





First 200 mm wafers with 3.5 millions NEMS (Caltech-LETI Alliance)

CMOS process – Micro electronics tools – 200mm wafers

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NEMS for gaz sensing at CEA-LETI



In-Plane piezo-resistive nano-resonators for gaz sensors



Gauge factor
$$\gamma = \frac{dR/R}{dL/L} = \frac{dR/R}{\epsilon}$$

Piezoresistive gauges Beam Driving electrode



« In-plane nanoelectromechanical resonators based on silicon nanowire piezoresistive detection », E. Mile et al., Nanotechnology 21, 165-504, 2010

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NEMS for gaz sensing at CEA-LETI



In-Plane piezo-resistive nano-resonators for gaz sensors



Vdrive=1.5V; Vbias=1.5V; Vacuum <1 mTorr Displacement 10 nm at Vdrive 3mV

Fr 19.16MHz (2% dispersion around 200mm wafer)
Q 5000-10000 in vacuum / Q 200 in air
SBR 67dB thank to:

* geometrical decoupling (driving electrodes and piezoresistive gauges)

* frequency decoupling (down-mixing measurement)



Vbias=1.5V - Noise computed for 1Hz-bandwith

- Noise floor very low and dominated by thermomechanical and electronic noise, rather than Johnson noise

Mass 140 fg, Q-factor of 5000, DR 100 dB → Allan deviation 1.5x10⁻⁹ over 1s-integration time → Potential mass resolution of ≈0.3 zg at room temperature and at 20 MHz

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From NEMS to Nanowires ...

NEMS/Nanowires resonators for ultrasensitive mass detection



Nano-resonators can enable few molecules mass detection in gaz or liquid environments

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Need for Integration of NEMS & Nanowires with CMOS



"Ultra-Sensitive Capacitive Detection Based on SGMOSFET Compatible with Front-End CMOS Process", E. Colinet et al., IEEE Journal of Solid-State Circuits, vol. 44 (1), 2009, pp. 247-257



Technological platforms developed in NEMSIC

General considerations

- Role of CEA-LETI in NEMSIC WP5: Advanced Technological Platforms for NEMSIC
- Integration of Nanowires + CMOS transistors on the same wafer
 - Nanowires: Diameter 40-50nm
 - Transistors: FDSOI technology
- SOI technology
- DRM & DK provided to partners to enable electrical simulation and layout
- Two dedicated platforms in CEA-LETI/MINATEC 200mm clean-rooms:
 - 1 for Sensing devices
 - 1 for Power Management devices
 - Issues:
 - Combine FDSOI technology and Nanowire technology
 - Open the platforms to the partners (EPFL, Univ of Southampton, LETI)



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DRM and DK for Nanowire - FDSOI integration

Design Kit for Nanowires - CMOS integration on FDSOI technology



Design-Layout Electrical simulation ELDO Physical verif & Layout Finishing

Graphics



Amplificator



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Stand-alone and Co-integrated ultra-scaled Si NEMS (LETI)

Cross-beam structures with electrostatic actuation and piezo-resistive detection



SEM view of stand-alone ultra-scaled Si NEMS (beam width 80nm, gauges 30nm wide, Si thickness 40nm)

Nanowires structures with with electrostatic actuation and piezo-resistive detection



SEM view of stand-alone ultra-scaled Si nanowire (beam width 40nm, thickness 40nm)

NEMS-CMOS co-integration will enable direct measurement of **NEMS** resonators



NEMS (nanowire 40x40nm cross-section) embedded in CMOS process

Electrical results will be reported later

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Fabrication of devices designed by NEMSIC partners



Please refer to talks given by EPFL and Univ of Southampton

Conclusion

NEMS & Nanowires are very attractive because of their intrinsic advantages and because they offer the possibility of innovating approaches for the sensors field and the CMOS industry

- Compactness and low cost
- Low power consumption (simplified analog circuit associated with NEMS)
- Good SNR (reduction of parasitics essential for NEMS/Nanowires)
- Convergence of Nanowires and CMOS technologies is a real opportunity
 - Down-scaling favorable to benefit of the advantages of NEMS/Nanowires
 - Arrays necessary for high performances and new generation of sensors
- NEMSIC aims to demonstrate benefit of Integration of Nanowires & CMOS
 - Stand-alone Nanowire-based devices
 - Innovative devices like Mixed Nanowire-Transistor devices by EPFL (VB-FET, SGFEt for power management) and Univ of Southampton (Lateral SG-FET)
 - Fully integrated Nanowire-based structures with CMOS (FDSOI) by LETI
 - CEA-LETI: fabrication of advanced devices on 200mm NEMS-FDSOI platforms
- Practical applications targetted in NEMSIC:
 - Resonant devices for gaz sensing (& bio applications)
 - Devices for power management in CMOS industry

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